

In the claims:

Please cancel claims 4-5 and 10-12.

Please amend claims 1, 3, 6, 9 and 13 as follows.

1. (currently amended) A device for testing integrated circuits comprising:

a base;

a socket body held in the base for contacting a plurality of terminals from an integrated circuit;

~~a lid having a top face, a first side and a second side, said first side and second side opposite each other across said top face~~ assembly including a pressure plate having a first and a second bearing assembly on opposing sides of said pressure plate;

a hinge joining said lid assembly to said base;

a locking mechanism allowing locking of said lid to said base;

~~a pressure plate retained within said lid;~~

~~a first and a second [[cam]] lever; respectively mechanically linked to said first side and said second side of the lid for lowering said pressure plate from said lid to said socket when the integrated circuit is placed within said socket.~~

a first and a second ratchet head each at one end of said first and said second lever respectively;

a plurality of teeth on an exterior circumference of each of said first and second ratchet head;

an arc groove on each of said first and said second ratchet head, wherein said first and second bearing assembly are each respectively disposed within said first and said second arc groove such that rotation of said ratchet head causes vertical movement of said pressure plate; and

a means for engaging said teeth, thereby preventing rotation of said first and said second ratchet head.

2. (original) The device of claim 1, further including a sight groove on the base, said sight groove allowing a user to view the integrated circuit within said test socket.

3. (currently amended) The device of claim 1, wherein said first and second ~~[[cam]] levers include first and second cam ratcheting levers with said cam ratcheting levers each having ratchet like notches, with each of said cam ratcheting levers having elongate arms, said arms~~ are joined by a linking bar.

4-5. (cancelled)

6. (currently amended) The device of claim ~~[[5]]~~ 1, wherein said ~~[[lock]]~~ means for engaging said teeth is spring biased.

7. (original) The device of claim 1, wherein said pressure plate may include an open central area through which the integrated circuit may be viewed.

8. (original) The device of claim 1, wherein said socket body includes pogo pins.

9. (currently amended) A device for testing integrated circuits comprising:

a base;

a socket body within said base for contacting a plurality of terminals from an integrated circuit;

~~a lid having a top face, a first side and a second side, said first side and second side opposite each other across said top face~~ assembly including a pressure plate having a first and a second bearing assembly on opposing sides of said pressure plate;

a hinge joining said lid to said base;

a locking mechanism allowing locking of said lid to said base;

a first and a second lever;

~~a pressure plate retained within said lid;~~

~~two means respectively on said first side and said second side of the lid for incrementally lowering said pressure plate from said lid to said integrated circuit when said integrated circuit is placed within said device;~~

a first and a second ratchet head each at one end of said first and said second lever respectively;

a plurality of teeth on an exterior circumference of each of said first and second ratchet head;

an arc groove on each of said first and said second ratchet head, wherein said first and second bearing assembly are each respectively disposed within said first and said second arc groove such that rotation of said first and second ratchet head causes vertical movement of said pressure plate;

a lock mechanism positioned to engage said teeth, thereby preventing rotation of said first and said second ratchet head; and

a sight groove which extends through said base to allow for visual examination of the integrated circuit during test.

10-12. (cancelled)

13. (Currently amended) The device of claim [[12]] 9, wherein said [[lock]] means for engaging said teeth is spring biased.

14. (original) The device of claim 9, wherein said pressure plate includes an open central area through which said integrated circuit may be viewed.

15. (original) The device of claim 9, wherein said socket body includes pogo pins.